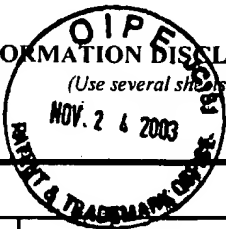


# INFORMATION DISCLOSURE CITATION

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Docket Number (Optional)  
DC4960

Application Number  
09/973,498

Applicant(s)  
Chaudhury, et. al.

Filing Date  
October 9, 2001

Group Art Unit  
1713

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							YES	NO
JTS		0 391 068	03/01/1990	Europe	—	—	✓	
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**09/973,498**

**Applicant(s)**

Chaudhury, et. al.

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	4,753,978	6/28/88	Jensen	524	862	
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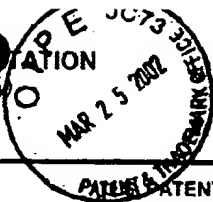
*John T. Huran*

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